- **Member of the Texas Instruments Widebus+™ Family**
- **Pinout Optimizes DDR-II DIMM PCB Layout**
- **Configurable as 25-Bit 1:1 or 14-Bit 1:2 Registered Buffer**
- **Chip-Select Inputs Gate the Data Outputs from Changing State and Minimizes System Power Consumption**
- **Output Edge-Control Circuitry Minimizes Switching Noise in an Unterminated Line**
- **Supports SSTL_18 Data Inputs**
- **Differential Clock (CLK and $\overline{\text{CLK}}$) Inputs**
- **Supports LVCMOS Switching Levels on the Control and $\overline{\text{RESET}}$ Inputs**
- **$\overline{\text{RESET}}$ Input Disables Differential Input Receivers, Resets All Registers, and Forces All Outputs Low**
- **Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II**
- **ESD Protection Exceeds JESD 22**
  - **5000-V Human-Body Model (A114-A)**
  - **200-V Machine Model (A115-A)**
  - **1000-V Charged-Device Model (C101)**

description/ordering information

This 25-bit 1:1 or 14-bit 1:2 configurable registered buffer is designed for 1.7-V to 1.9-V V_{CC} operation. In the 1:1 pinout configuration, only one device per DIMM is required to drive nine SDRAM loads. In the 1:2 pinout configuration, two devices per DIMM are required to drive 18 SDRAM loads.

All inputs are SSTL_18, except the LVCMOS reset ($\overline{\text{RESET}}$) and LVCMOS control (Cn) inputs. All outputs are edge-controlled circuits optimized for unterminated DIMM loads and meet SSTL_18 specifications.

The SN74SSTU32864 operates from a differential clock (CLK and $\overline{\text{CLK}}$). Data are registered at the crossing of CLK going high and $\overline{\text{CLK}}$ going low.

The C0 input controls the pinout configuration of the 1:2 pinout from register-A configuration (when low) to register-B configuration (when high). The C1 input controls the pinout configuration from 25-bit 1:1 (when low) to 14-bit 1:2 (when high). C0 and C1 should not be switched during normal operation. They should be hard-wired to a valid low or high level to configure the register in the desired mode. In the 25-bit 1:1 pinout configuration, the A6, D6, and H6 terminals are driven low and should not be used.

The device supports low-power standby operation. When $\overline{\text{RESET}}$ is low, the differential input receivers are disabled, and undriven (floating) data, clock, and reference voltage (V_{REF}) inputs are allowed. In addition, when $\overline{\text{RESET}}$ is low, all registers are reset and all outputs are forced low. The LVCMOS $\overline{\text{RESET}}$ and Cn inputs always must be held at a valid logic high or low level.

The two V_{REF} pins (A3 and T3), are connected together internally by approximately 150 Ω. However, it is necessary to connect only one of the two V_{REF} pins to the external V_{REF} power supply. An unused V_{REF} pin should be terminated with a V_{REF} coupling capacitor.

ORDERING INFORMATION

T_A	PACKAGE†		ORDERABLE PART NUMBER	TOP-SIDE MARKING
0°C to 70°C	LFBGA – GKE	Tape and reel	SN74SSTU32864GKER	SU864

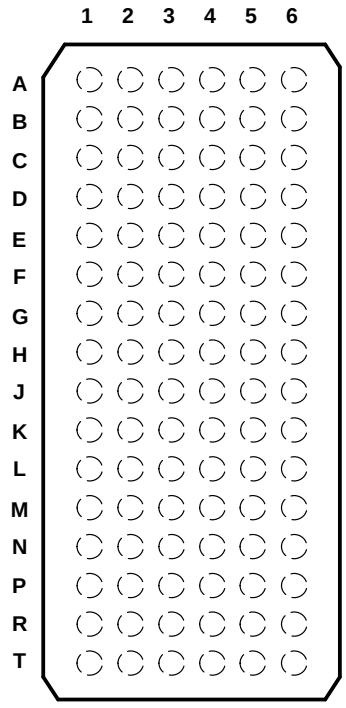
† Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

description/ordering information (continued)

The device also supports low-power active operation by monitoring both system chip select ($\overline{DCS}$ and $\overline{CSR}$) inputs and will gate the Qn outputs from changing states when both $\overline{DCS}$ and $\overline{CSR}$ inputs are high. If either $\overline{DCS}$ or $\overline{CSR}$ input is low, the Qn outputs function normally. The $\overline{RESET}$ input has priority over the $\overline{DCS}$ and $\overline{CSR}$ control and forces the output low. If the $\overline{DCS}$ control functionality is not desired, the $\overline{CSR}$ input can be hard-wired to ground, in which case, the setup-time requirement for $\overline{DCS}$ is the same as for the other D data inputs.

To ensure defined outputs from the register before a stable clock has been supplied, $\overline{RESET}$ must be held in the low state during power up.

GKE PACKAGE
(TOP VIEW)

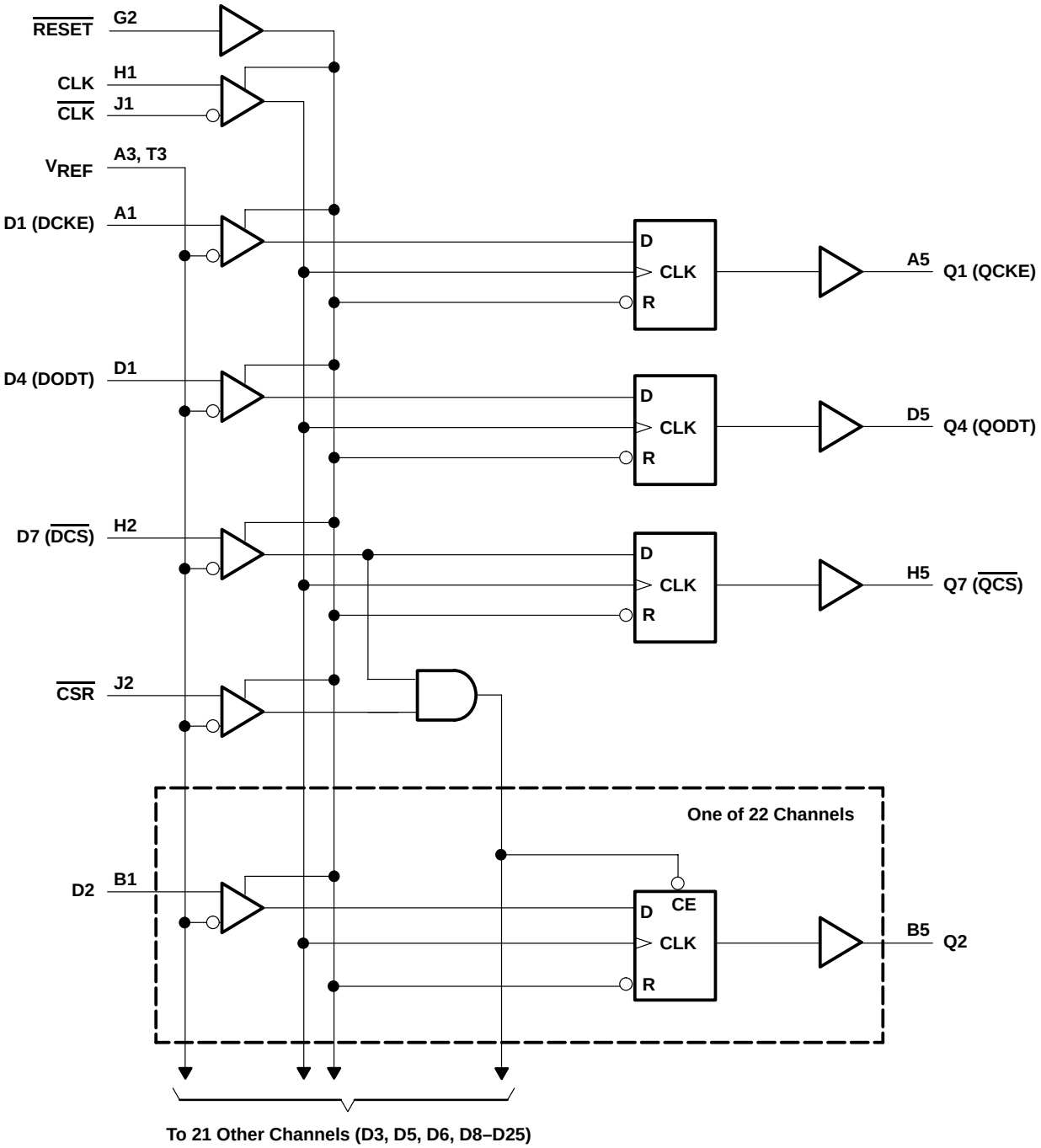


terminal assignments for 1:1 register (C0 = 0, C1 = 0)

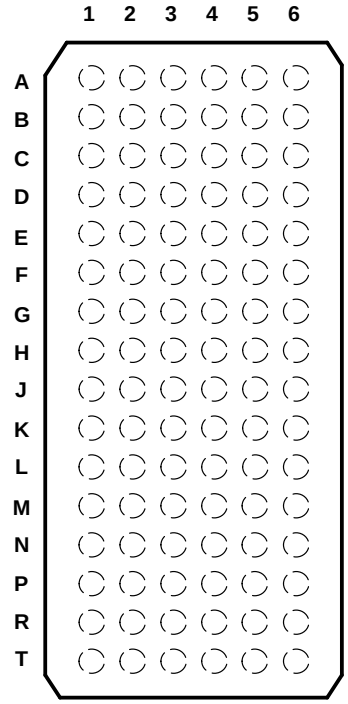
	1	2	3	4	5	6
A	D1 (DCKE)	NC	V_{REF}	V_{CC}	Q1 (QCKE)	DNU
B	D2	D15	GND	GND	Q2	Q15
C	D3	D16	V_{CC}	V_{CC}	Q3	Q16
D	D4 (DODT)	NC	GND	GND	Q4 (QODT)	DNU
E	D5	D17	V_{CC}	V_{CC}	Q5	Q17
F	D6	D18	GND	GND	Q6	Q18
G	NC	$\overline{RESET}$	V_{CC}	V_{CC}	C1	C0
H	CLK	D7 ($\overline{DCS}$)	GND	GND	Q7 ($\overline{QCS}$)	DNU
J	$\overline{CLK}$	$\overline{CSR}$	V_{CC}	V_{CC}	NC	NC
K	D8	D19	GND	GND	Q8	Q19
L	D9	D20	V_{CC}	V_{CC}	Q9	Q20
M	D10	D21	GND	GND	Q10	Q21
N	D11	D22	V_{CC}	V_{CC}	Q11	Q22
P	D12	D23	GND	GND	Q12	Q23
R	D13	D24	V_{CC}	V_{CC}	Q13	Q24
T	D14	D25	V_{REF}	V_{CC}	Q14	Q25

Each pin name in parentheses indicates the DDR-II DIMM signal name.
NC – No internal connection
DNU – Do not use

logic diagram for 1:1 register configuration (positive logic)



GKE PACKAGE
(TOP VIEW)

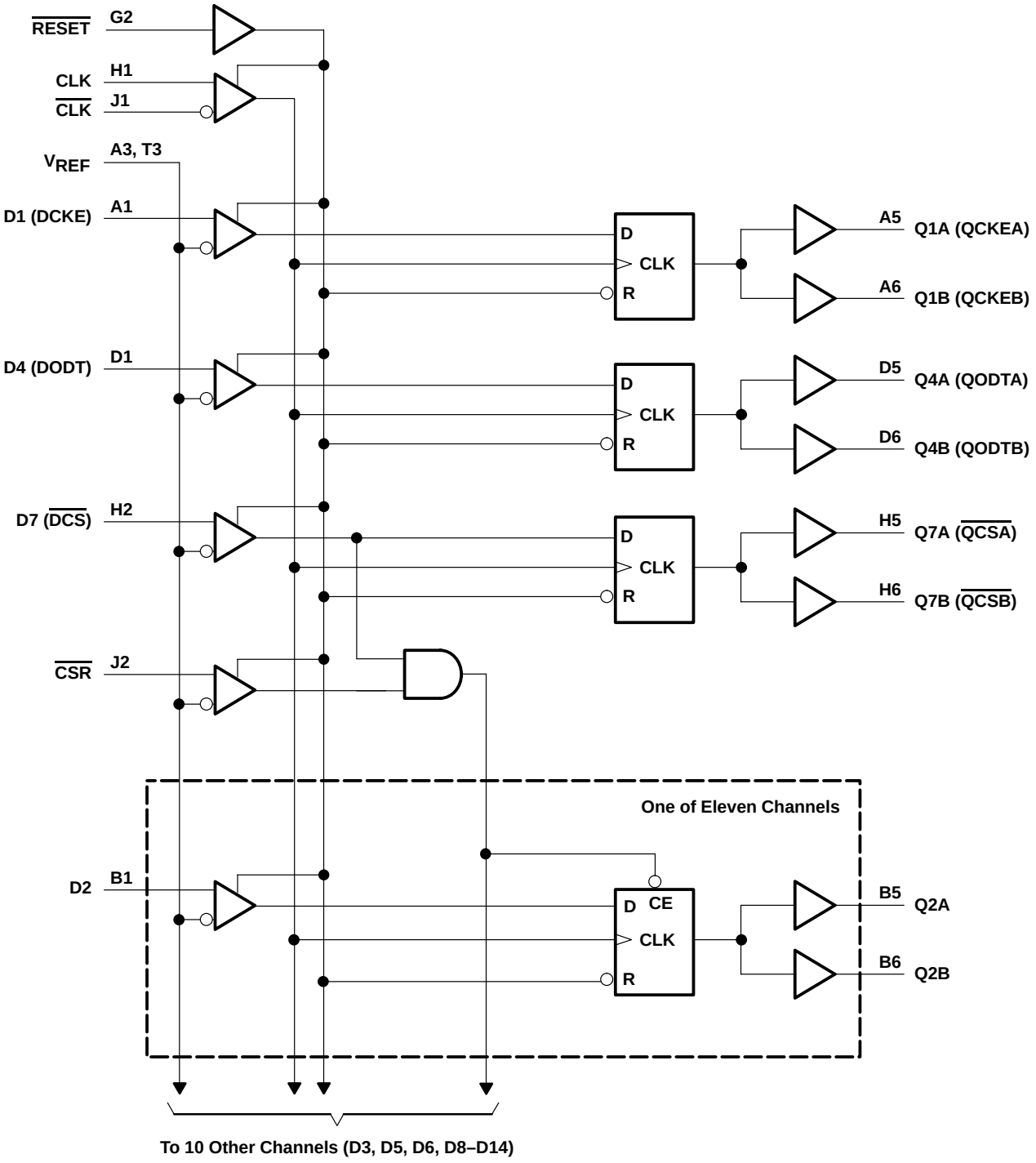


terminal assignments for 1:2 register A (C0 = 0, C1 = 1)

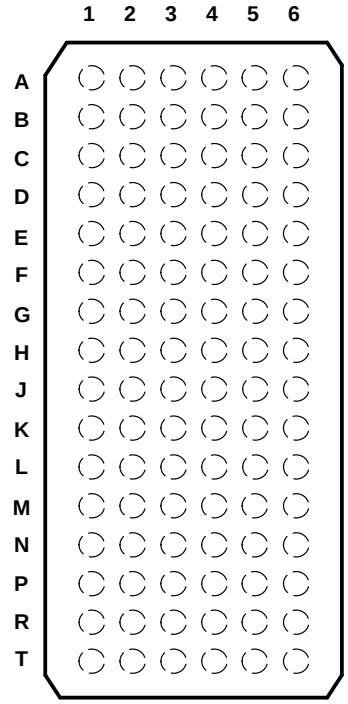
	1	2	3	4	5	6
A	D1 (DCKE)	NC	V_{REF}	V_{CC}	Q1A (QCKEA)	Q1B (QCKEB)
B	D2	DNU	GND	GND	Q2A	Q2B
C	D3	DNU	V_{CC}	V_{CC}	Q3A	Q3B
D	D4 (DODT)	NC	GND	GND	Q4A (QODTA)	Q4B (QODTB)
E	D5	DNU	V_{CC}	V_{CC}	Q5A	Q5B
F	D6	DNU	GND	GND	Q6A	Q6B
G	NC	$\overline{\text{RESET}}$	V_{CC}	V_{CC}	C1	C0
H	CLK	D7 ($\overline{\text{DCS}}$)	GND	GND	$\overline{\text{Q7A}}$ ($\overline{\text{QCSA}}$)	$\overline{\text{Q7B}}$ ($\overline{\text{QCSB}}$)
J	$\overline{\text{CLK}}$	$\overline{\text{CSR}}$	V_{CC}	V_{CC}	NC	NC
K	D8	DNU	GND	GND	Q8A	Q8B
L	D9	DNU	V_{CC}	V_{CC}	Q9A	Q9B
M	D10	DNU	GND	GND	Q10A	Q10B
N	D11	DNU	V_{CC}	V_{CC}	Q11A	Q11B
P	D12	DNU	GND	GND	Q12A	Q12B
R	D13	DNU	V_{CC}	V_{CC}	Q13A	Q13B
T	D14	DNU	V_{REF}	V_{CC}	Q14A	Q14B

Each pin name in parentheses indicates the DDR-II DIMM signal name.
NC – No internal connection
DNU – Do not use

logic diagram 1:2 register-A configuration (positive logic)



GKE PACKAGE
(TOP VIEW)

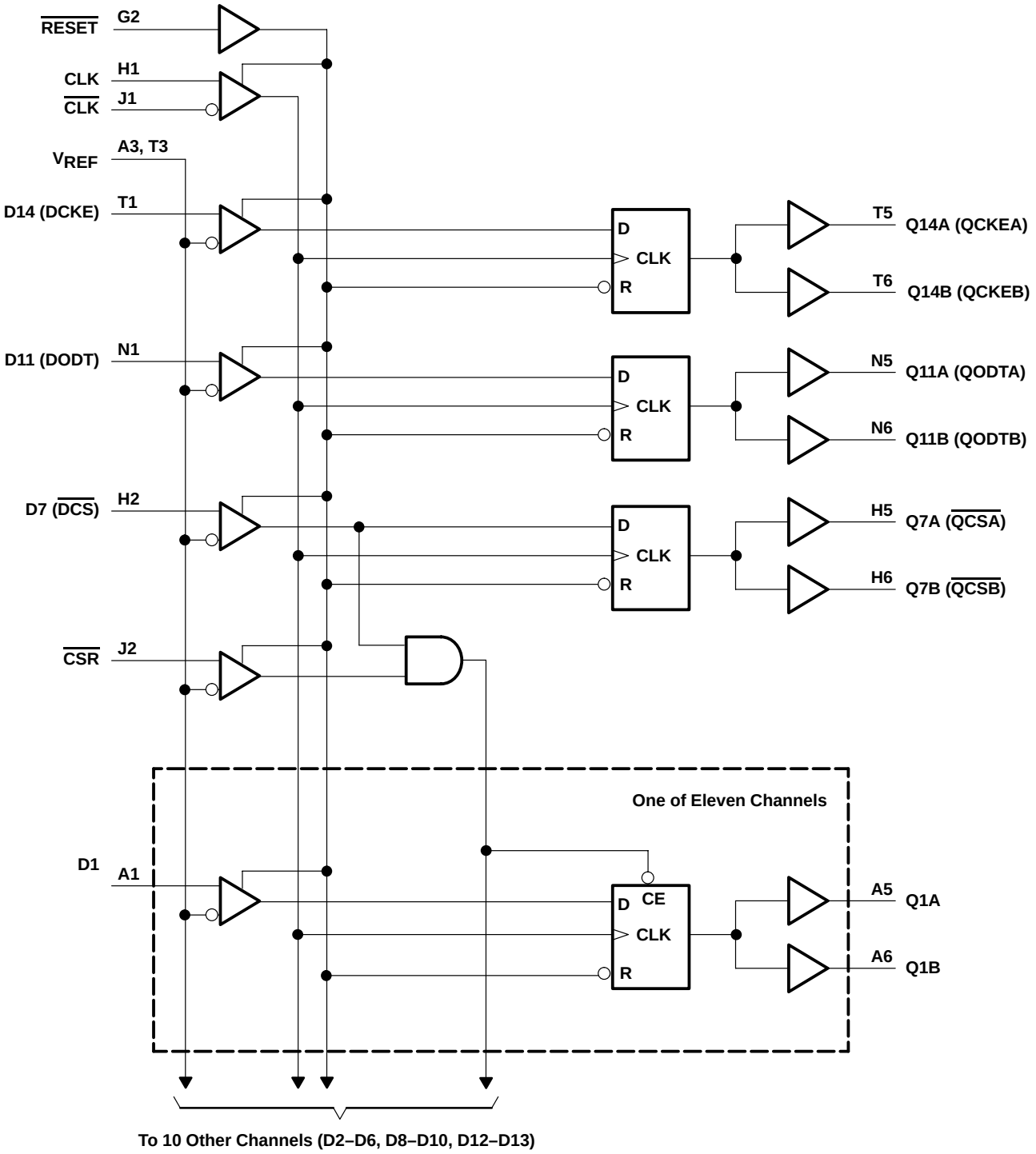


terminal assignments for 1:2 register B (C0 = 1, C1 = 1)

	1	2	3	4	5	6
A	D1	NC	V_{REF}	V_{CC}	Q1A	Q1B
B	D2	DNU	GND	GND	Q2A	Q2B
C	D3	DNU	V_{CC}	V_{CC}	Q3A	Q3B
D	D4	NC	GND	GND	Q4A	Q4B
E	D5	DNU	V_{CC}	V_{CC}	Q5A	Q5B
F	D6	DNU	GND	GND	Q6A	Q6B
G	NC	$\overline{\text{RESET}}$	V_{CC}	V_{CC}	C1	C0
H	CLK	D7 ($\overline{\text{DCS}}$)	GND	GND	$\overline{\text{Q7A}}$ ($\overline{\text{QCSA}}$)	$\overline{\text{Q7B}}$ ($\overline{\text{QCSB}}$)
J	$\overline{\text{CLK}}$	$\overline{\text{CSR}}$	V_{CC}	V_{CC}	NC	NC
K	D8	DNU	GND	GND	Q8A	Q8B
L	D9	DNU	V_{CC}	V_{CC}	Q9A	Q9B
M	D10	DNU	GND	GND	Q10A	Q10B
N	D11 (DODT)	DNU	V_{CC}	V_{CC}	Q11A (QODTA)	Q11B (QODTB)
P	D12	DNU	GND	GND	Q12A	Q12B
R	D13	DNU	V_{CC}	V_{CC}	Q13A	Q13B
T	D14 (DCKE)	DNU	V_{REF}	V_{CC}	Q14A (QCKEA)	Q14B (QCKEB)

Each pin name in parentheses indicates the DDR-II DIMM signal name.
NC – No internal connection
DNU – Do not use

logic diagram 1:2 register-B configuration (positive logic)



TERMINAL FUNCTIONS

TERMINAL NAME	DESCRIPTION	ELECTRICAL CHARACTERISTICS
GND	Ground	Ground input
V_{CC}	Power-supply voltage	1.8 V nominal
V_{REF}	Input reference voltage	0.9 V nominal
CLK	Positive master clock input	Differential input
$\overline{CLK}$	Negative master clock input	Differential input
C0, C1	Configuration control inputs – Register A, Register B, 1:1, 1:2 select	LVCMOS inputs
$\overline{RESET}$	Asynchronous reset input – resets registers and disables V_{REF} data and clock differential-input receivers	LVCMOS input
D1–D25	Data inputs – clocked in on the crossing of the rising edge of CLK and the falling edge of $\overline{CLK}$	SSTL_18 inputs
$\overline{CSR}$, $\overline{DCS}$	Chip select inputs – disables D1-D25† outputs switching when both inputs are high	SSTL_18 inputs
DODT	The outputs of this register bit will not be suspended by the $\overline{DCS}$ and $\overline{CSR}$ control.	SSTL_18 input
DCKE	The outputs of this register bit will not be suspended by the $\overline{DCS}$ and $\overline{CSR}$ control.	SSTL_18 input
Q1–Q25‡	Data outputs that are suspended by the $\overline{DCS}$ and $\overline{CSR}$ control	1.8 V CMOS outputs
$\overline{QCS}$	Data output that will not be suspended by the $\overline{DCS}$ and $\overline{CSR}$ control	1.8 V CMOS output
QODT	Data output that will not be suspended by the $\overline{DCS}$ and $\overline{CSR}$ control	1.8 V CMOS output
QCKE	Data output that will not be suspended by the $\overline{DCS}$ and $\overline{CSR}$ control	1.8 V CMOS output
NC	No internal connection	
DNU	Do not use – inputs are in standby-equivalent mode, and outputs are driven low.	

† Data inputs = D2, D3, D5, D6, D8–D25 when C0 = 0 and C1 = 0
Data inputs = D2, D3 D5, D6, D8–D14 when C0 = 0 and C1 = 1
Data inputs = D1–D6, D8–D10, D12, D13 when C0 = 1 and C1 = 1.

‡ Data outputs = Q2, Q3, Q5, Q6, Q8–Q25 when C0 = 0 and C1 = 0
Data outputs = Q2, Q3 Q5, Q6, Q8–Q14 when C0 = 0 and C1 = 1
Data outputs = Q1–Q6, Q8–Q10, Q12, Q13 when C0 = 1 and C1 = 1.

FUNCTION TABLES

INPUTS						OUTPUT
$\overline{\text{RESET}}$	$\overline{\text{DCS}}$	$\overline{\text{CSR}}$	CLK	$\overline{\text{CLK}}$	Dn	Qn
H	L	X	↑	↓	L	L
H	L	X	↑	↓	H	H
H	X	L	↑	↓	L	L
H	X	L	↑	↓	H	H
H	H	H	↑	↓	X	Q_0
H	X	X	L or H	L or H	X	Q_0
L	X or floating	X or floating	X or floating	X or floating	X or floating	L

INPUTS				OUTPUTS
$\overline{\text{RESET}}$	CLK	$\overline{\text{CLK}}$	DCKE, $\overline{\text{DCS}}$, DODT	$\overline{\text{QCKE}}$, $\overline{\text{QCS}}$, QODT
H	↑	↓	H	H
H	↑	↓	L	L
H	L or H	L or H	X	Q_0
L	X or floating	X or floating	X or floating	L

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC} . . . . . –0.5 V to 2.5 V
Input voltage range, V_I (see Notes 1 and 2) . . . . . –0.5 V to 2.5 V
Output voltage range, V_O (see Notes 1 and 2) . . . . . –0.5 V to V_{CC} + 0.5 V
Input clamp current, I_{IK} (V_I < 0 or V_I > V_{CC}) . . . . . ±50 mA
Output clamp current, I_{OK} (V_O < 0 or V_O > V_{CC}) . . . . . ±50 mA
Continuous output current, I_O (V_O = 0 to V_{CC}) . . . . . ±50 mA
Continuous current through each V_{CC} or GND . . . . . ±100 mA
Package thermal impedance, θ_{JA} (see Note 3) . . . . . 36°C/W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. This value is limited to 2.5 V maximum.
3. The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Note 4)

			MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage		1.7		1.9	V
V_{REF}	Reference voltage		$0.49 \times V_{CC}$	$0.5 \times V_{CC}$	$0.51 \times V_{CC}$	V
V_I	Input voltage		0		V_{CC}	V
V_{IH}	AC high-level input voltage	Data inputs, $\overline{CSR}$	V_{REF}+250 mV			V
V_{IL}	AC low-level input voltage	Data inputs, $\overline{CSR}$			V_{REF}–250 mV	V
V_{IH}	DC high-level input voltage	Data inputs, $\overline{CSR}$	V_{REF}+125 mV			V
V_{IL}	DC low-level input voltage	Data inputs, $\overline{CSR}$			V_{REF}–125 mV	V
V_{IH}	High-level input voltage	$\overline{RESET}$, Cn	$0.65 \times V_{CC}$			V
V_{IL}	Low-level input voltage	$\overline{RESET}$, Cn			$0.35 \times V_{CC}$	V
V_{ICR}	Common-mode input voltage range	CLK, $\overline{CLK}$	0.675		1.125	V
$V_{I(PP)}$	Peak-to-peak input voltage	CLK, $\overline{CLK}$	600			mV
I_{OH}	High-level output current				–8	mA
I_{OL}	Low-level output current				8	mA
T_A	Operating free-air temperature		0		70	°C

NOTE 4: The $\overline{RESET}$ and Cn inputs of the device must be held at valid logic voltage levels (not floating) to ensure proper device operation. The differential inputs must not be floating unless $\overline{RESET}$ is low. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		V_{CC}	MIN	TYP†	MAX	UNIT
V_{OH}		I_{OH} = –100 μA		1.7 V to 1.9 V	V_{CC}–0.2			V
		I_{OH} = –6 mA		1.7 V	1.2			
V_{OL}		I_{OL} = 100 μA		1.7 V to 1.9 V			0.2	V
		I_{OL} = 6 mA		1.7 V			0.5	
I_I	All inputs‡	$V_I = V_{CC}$ or GND		1.9 V			±5	μA
I_{CC}	Static standby	$\overline{RESET}$ = GND	I_O = 0	1.9 V			100	μA
	Static operating	$\overline{RESET} = V_{CC}$, $V_I = V_{IH(AC)}$ or $V_{IL(AC)}$					40	mA
I_{CCD}	Dynamic operating – clock only	$\overline{RESET} = V_{CC}$, $V_I = V_{IH(AC)}$ or $V_{IL(AC)}$, CLK and $\overline{CLK}$ switching 50% duty cycle	I_O = 0	1.8 V		28		μA/ MHz
	Dynamic operating – per each data input, 1:1 configuration	$\overline{RESET} = V_{CC}$, $V_I = V_{IH(AC)}$ or $V_{IL(AC)}$, CLK and $\overline{CLK}$ switching 50% duty cycle, One data input switching at one-half clock frequency, 50% duty cycle				18		μA/ clock MHz/ D input
	Dynamic operating – per each data input, 1:2 configuration					36		
I_{CCDLP}	Chip-select-enabled low-power active mode – clock only	$\overline{RESET} = V_{CC}$, $V_I = V_{IH(AC)}$ or $V_{IL(AC)}$, CLK and $\overline{CLK}$ switching 50% duty cycle	I_O = 0	1.8 V		27		μA/ MHz
	Chip-select-enabled low-power active mode – 1:1 configuration	$\overline{RESET} = V_{CC}$, $V_I = V_{IH(AC)}$ or $V_{IL(AC)}$, CLK and $\overline{CLK}$ switching 50% duty cycle, One data input switching at one-half clock frequency, 50% duty cycle				2		μA/ clock MHz/ D input
	Chip-select-enabled low-power active mode – 1:2 configuration					2		
C_i	Data inputs, $\overline{CSR}$	$V_I = V_{REF}$ ± 250 mV		1.8 V	2.5	3	3.5	pF
	CLK, $\overline{CLK}$	V_{ICR} = 0.9 V, $V_{I(PP)}$ = 600 mV			2		3	
	$\overline{RESET}$	$V_I = V_{CC}$ or GND				2.5		

† All typical values are at V_{CC} = 1.8 V, T_A = 25°C.
‡ Each V_{REF} pin (A3 or T3) should be tested independently, with the other (untested) pin open.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1 and Note 5)

			MIN	MAX	UNIT
f_{clock}	Clock frequency			500	MHz
t_w	Pulse duration, CLK, $\overline{CLK}$ high or low		1		ns
t_{act}	Differential inputs active time (see Note 6)			10	ns
t_{inact}	Differential inputs inactive time (see Note 7)			15	ns
t_{su}	Setup time	$\overline{DCS}$ before CLK↑, $\overline{CLK}$↓, $\overline{CSR}$ high; $\overline{CSR}$ before CLK↑, $\overline{CLK}$↓, $\overline{DCS}$ high	0.7		ns
		$\overline{DCS}$ before CLK↑, $\overline{CLK}$↓, $\overline{CSR}$ low	0.5		
		DODT, DCKE, and Data before CLK↑, $\overline{CLK}$↓	0.5		
t_h	Hold time	$\overline{DCS}$, DODT, DCKE, and Data after CLK↑, $\overline{CLK}$↓	0.5		ns

NOTES: 5. All input slew rates are 1 V/ns ±20%.
6. V_{REF} must be held at a valid input level and data inputs must be held low for a minimum time of t_{act} max, after $\overline{RESET}$ is taken high.
7. V_{REF}, data, and clock inputs must be held at valid voltage levels (not floating) for a minimum time of t_{inact} max, after $\overline{RESET}$ is taken low.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 1.8 V ± 0.1 V		UNIT
			MIN	MAX	
f_{max}			500		MHz
t_{pdm}†	CLK and $\overline{CLK}$	Q	1.4	2.5	ns
t_{pdmss}†	CLK and $\overline{CLK}$	Q		2.7	ns
t_{RPHL}†	$\overline{RESET}$	Q		3	ns

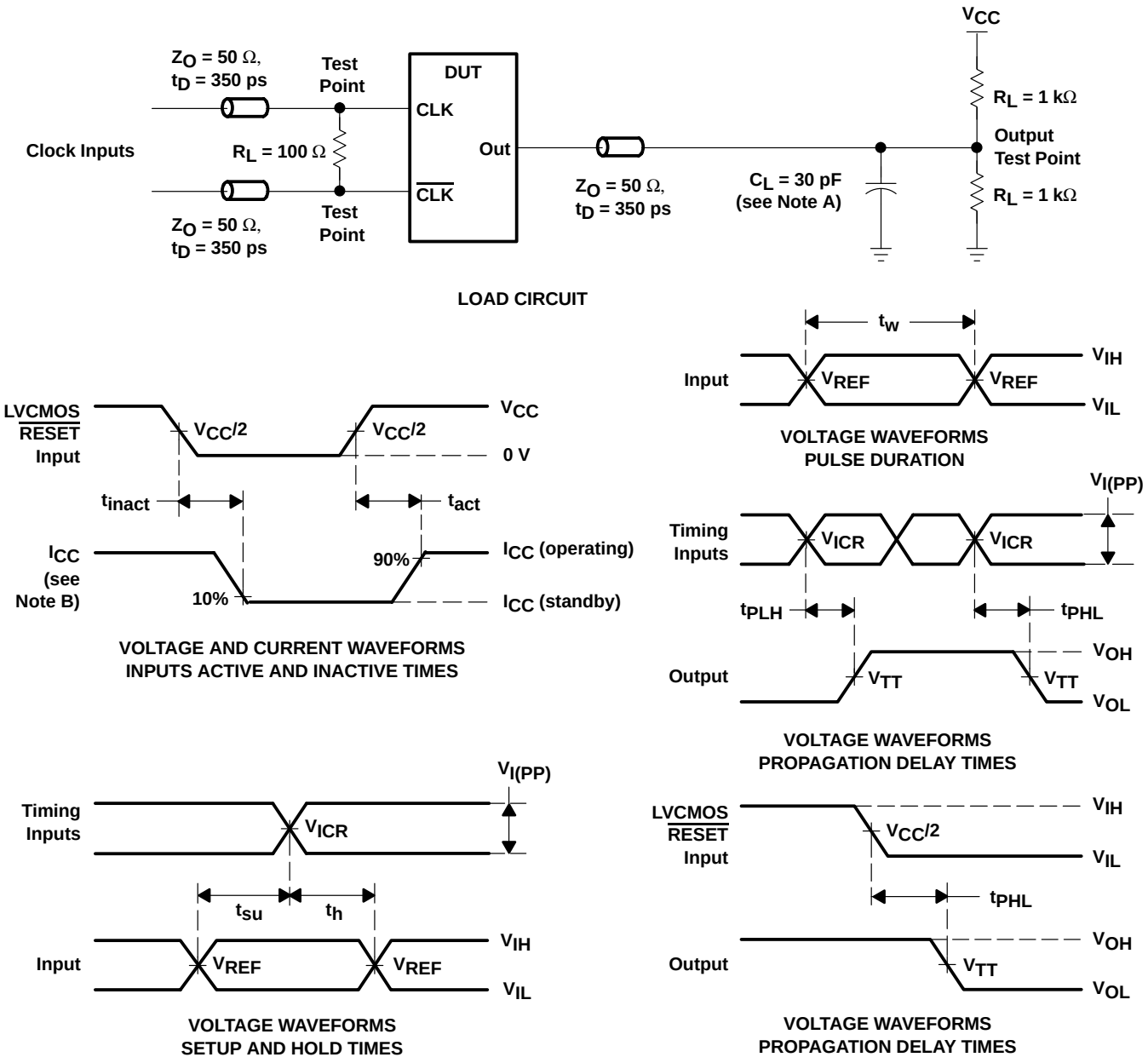
† Includes 350-ps test-load transmission-line delay

output slew rates over recommended operating free-air temperature range (unless otherwise noted) (see Figure 2)

PARAMETER	FROM	TO	V_{CC} = 1.8 V ± 0.1 V		UNIT
			MIN	MAX	
dV/dt_r	20%	80%	1.9	4.9	V/ns
dV/dt_f	80%	20%	1.9	4.9	V/ns
dV/dt_Δ§	20% or 80%	80% or 20%		1	V/ns

§ Difference between dV/dt_r (rising edge rate) and dV/dt_f (falling edge rate)

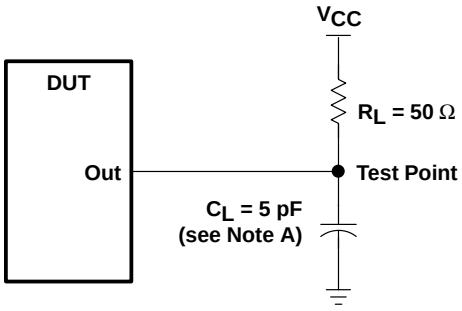
PARAMETER MEASUREMENT INFORMATION



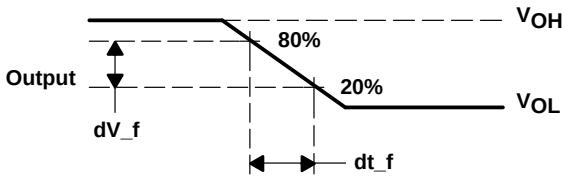
NOTES:
A. C_L includes probe and jig capacitance.
B. I_{CC} tested with clock and data inputs held at V_{CC} or GND, and I_O = 0 mA.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, input slew rate = 1 V/ns ±20% (unless otherwise noted).
D. The outputs are measured one at a time with one transition per measurement.
E. $V_{REF} = V_{CC}/2$
F. $V_{IH} = V_{REF}$ + 250 mV (ac voltage levels) for differential inputs. $V_{IH} = V_{CC}$ for LVCMOS input.
G. $V_{IL} = V_{REF}$ – 250 mV (ac voltage levels) for differential inputs. V_{IL} = GND for LVCMOS input.
H. $V_{I(PP)}$ = 600 mV
I. t_{PLH} and t_{PHL} are the same as t_{pd}.

Figure 1. Load Circuit and Voltage Waveforms

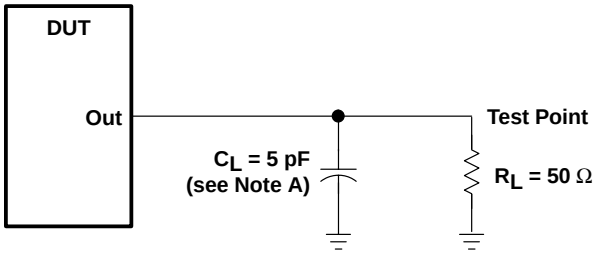
PARAMETER MEASUREMENT INFORMATION



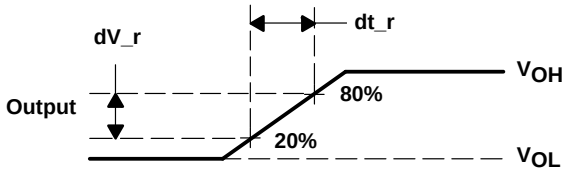
LOAD CIRCUIT
HIGH-TO-LOW SLEW-RATE MEASUREMENT



VOLTAGE WAVEFORMS
HIGH-TO-LOW SLEW-RATE MEASUREMENT



LOAD CIRCUIT
LOW-TO-HIGH SLEW-RATE MEASUREMENT



VOLTAGE WAVEFORMS
LOW-TO-HIGH SLEW-RATE MEASUREMENT

NOTES: A. C_L includes probe and jig capacitance.
B. All input pulses are supplied by generators having the following characteristics:
PRR ≤ 10 MHz, Z_O = 50 Ω, input slew rate = 1 V/ns ± 20% (unless otherwise specified).

Figure 2. Output Slew-Rate Measurement Information

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
SN74SSTU32864NMJR	ACTIVE	NFBGA	NMJ	96	1000	RoHS & Green	SNAGCU	Level-3-260C-168 HR	0 to 70	SU864	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

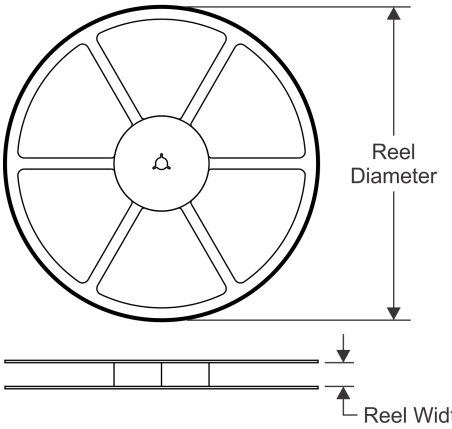
(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

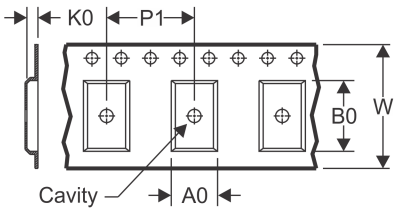
(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

TAPE AND REEL INFORMATION

REEL DIMENSIONS

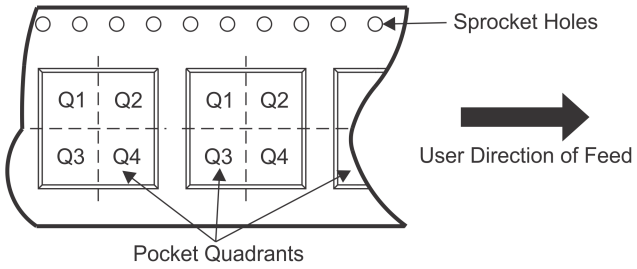


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

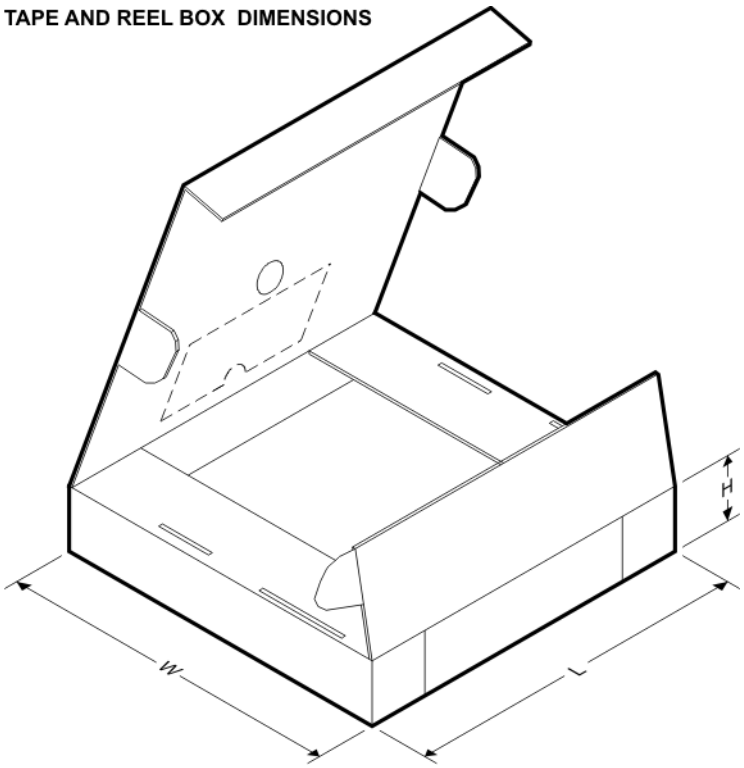
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74SSTU32864NMJR	NFBGA	NMJ	96	1000	330.0	24.4	5.85	13.85	1.8	8.0	24.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

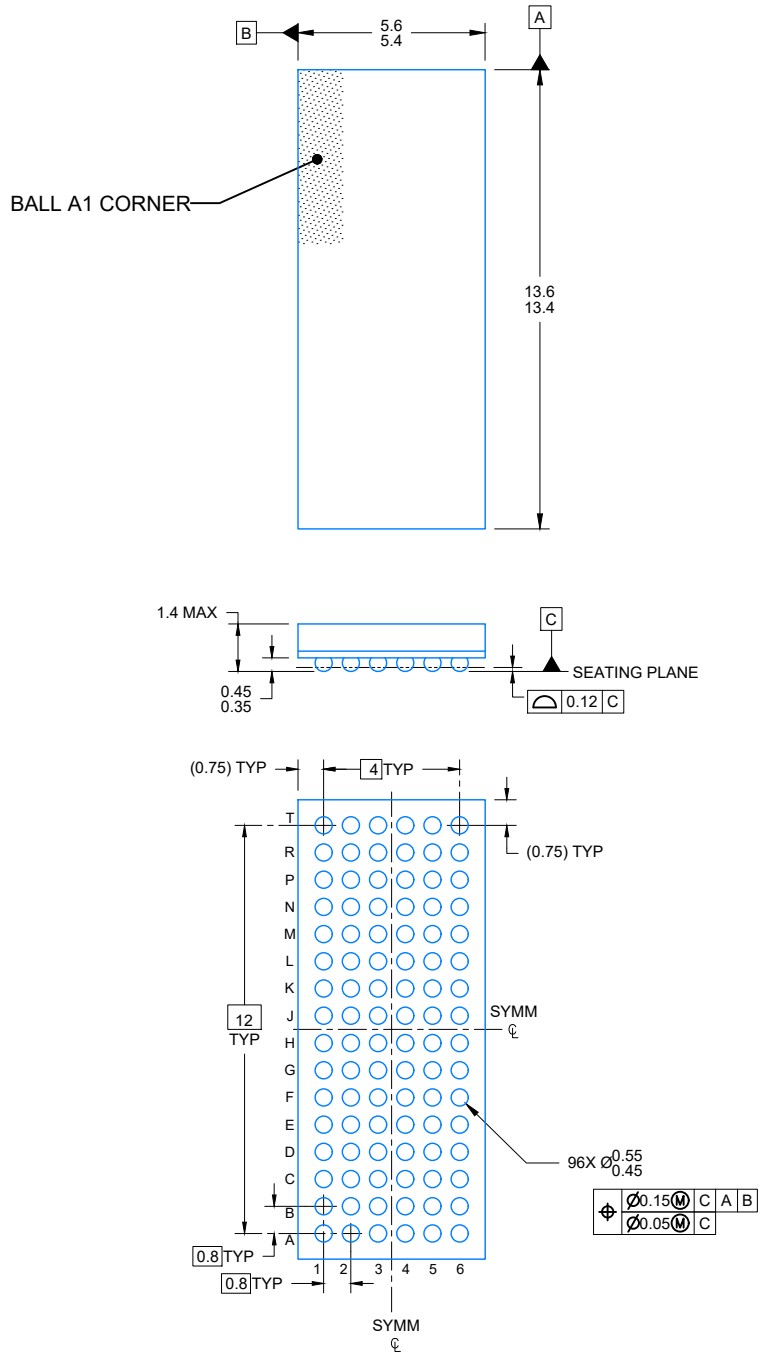
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74SSTU32864NMJR	NFBGA	NMJ	96	1000	336.6	336.6	41.3

PACKAGE OUTLINE

NMJ0096A

NFBGA - 1.4 mm max height

PLASTIC BALL GRID ARRAY



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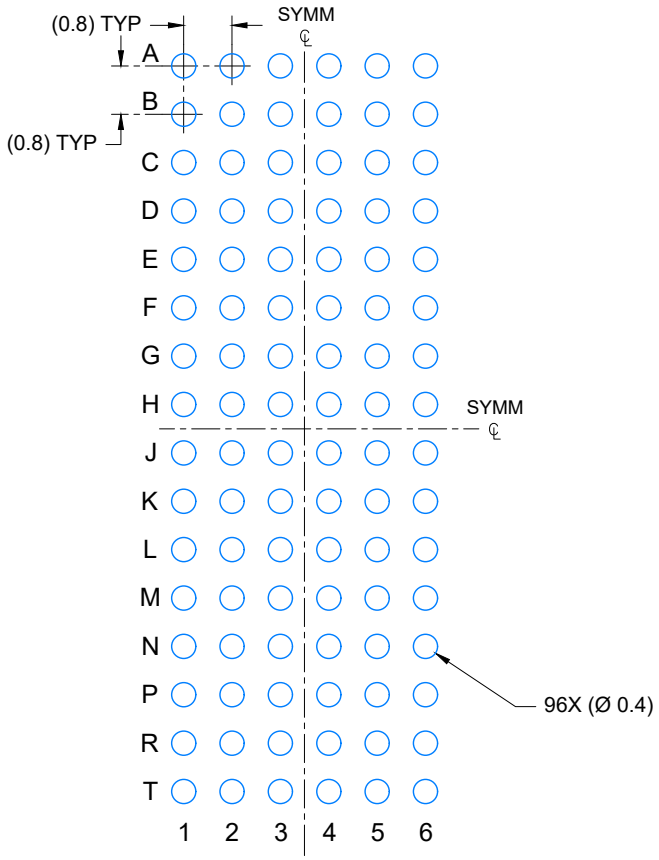
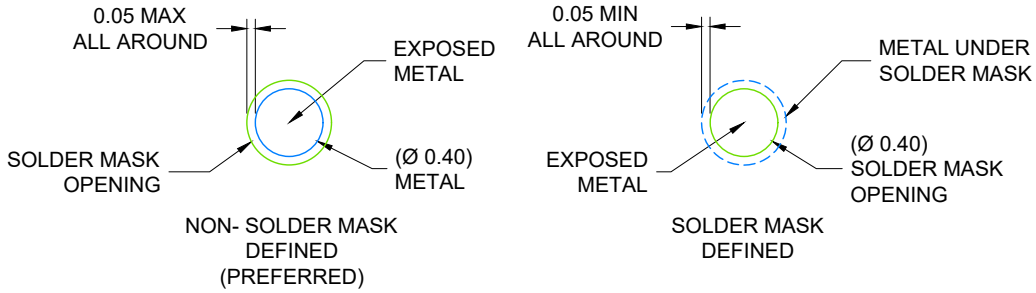
NOTES:

NanoFree is a trademark of Texas Instruments.

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.



LAND PATTERN EXAMPLE
SCALE: 8X



SOLDER MASK DETAILS
NOT TO SCALE

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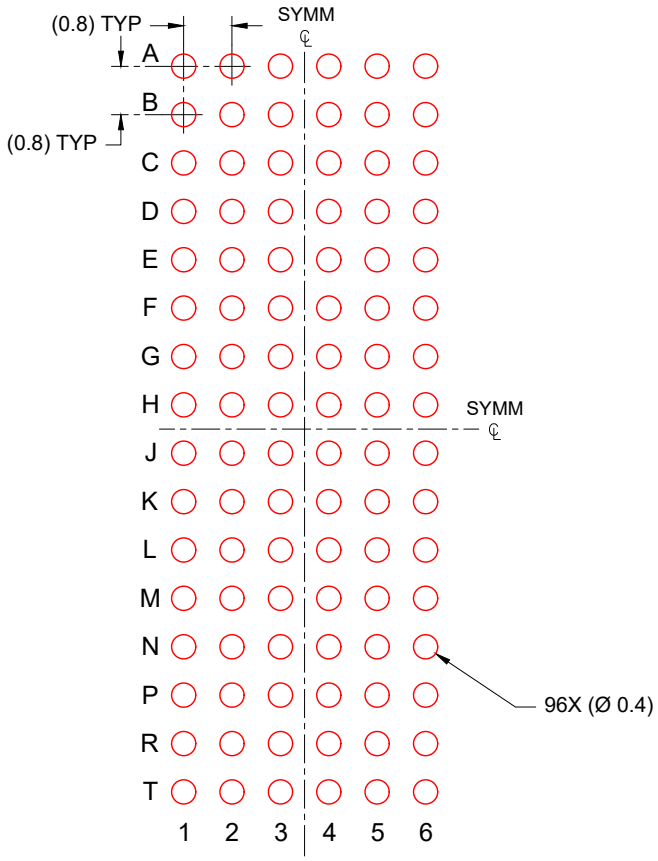
NOTES: (continued)

3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. Refer to Texas Instruments Literature number SNVA009 (www.ti.com/lit/snva009).



SOLDER PASTE EXAMPLE
BASED ON 0.150 mm THICK STENCIL
SCALE: 8X

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NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.

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